

Supplementary Materials

2.2.2. Scanning Electron Microscopy of a film surface

The following SEM images were acquired using a Hitachi Regulus 8220 Scanning Electron Microscope (Mito, Japan).

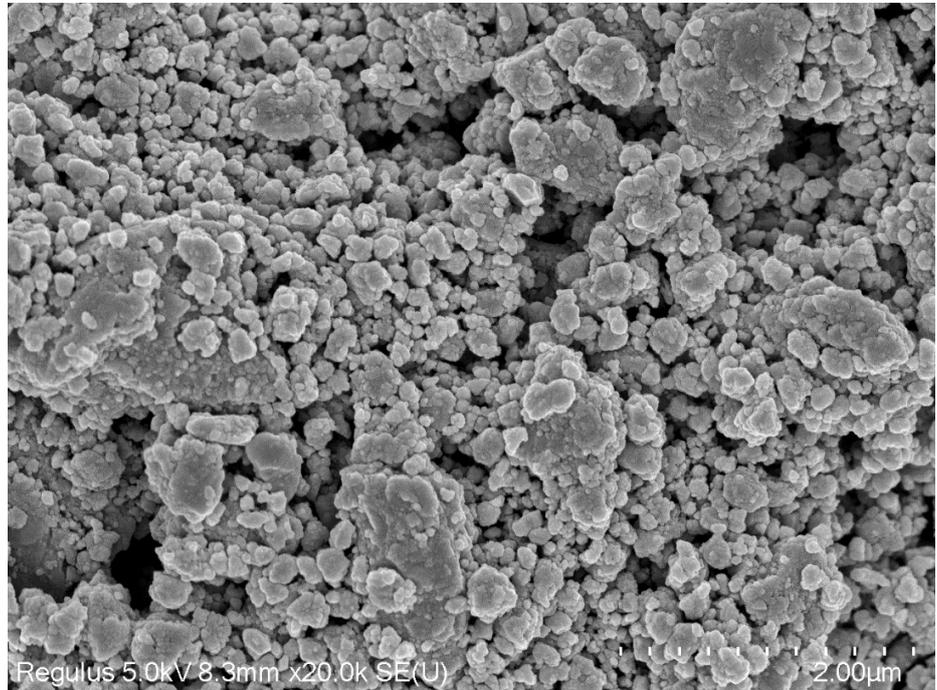


Figure S1. SEM image of the TiCe-0.8:0.2-40 sample at the center of the paste region.

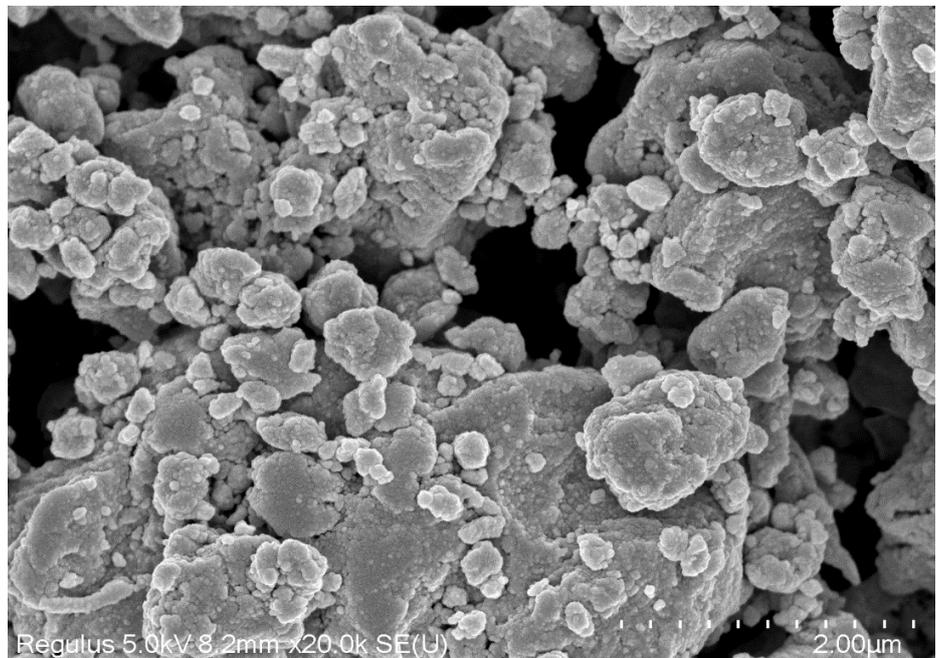


Figure S2. SEM image of the TiCe-0.2:0.8-40 sample at the center of the paste region.

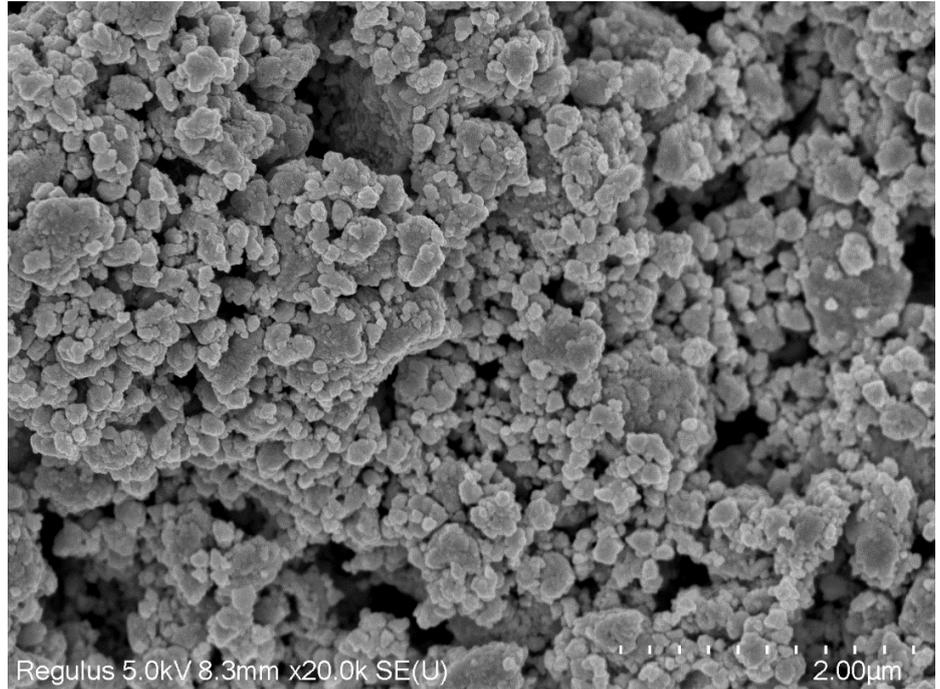


Figure S3. SEM image of the TiCe-0.8:0.2-100 sample at the center of the paste region.

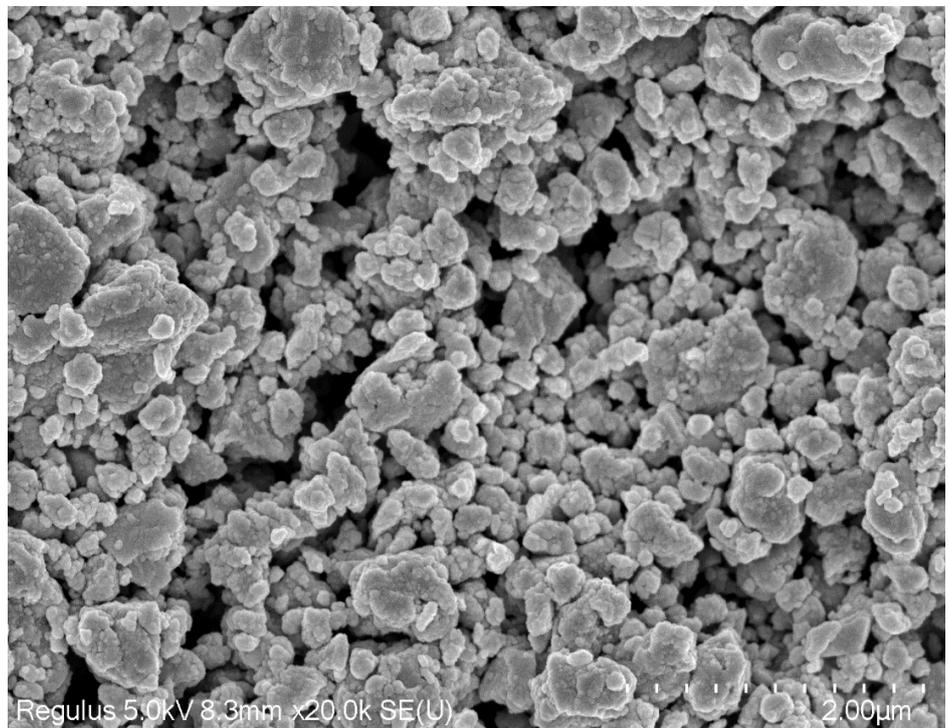


Figure S4. SEM image of the TiCe-0.2:0.8-100 sample at the center of the paste region.

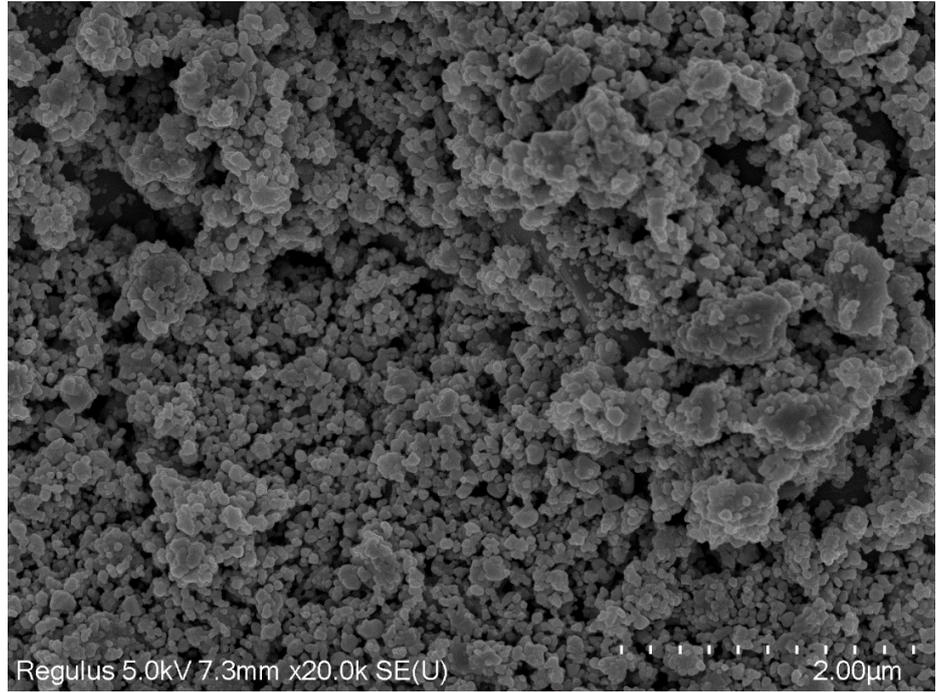


Figure S5. SEM image of the TiCe-0.5:0.5-100 sample at the center of the paste region.